

2007 Symposium on Nano Device Technology

The Symposium on Nano Device Technology 2007 organized by National Nano Device NARL, will provide an open forum for the discussion of recent developments on nano-technology and advanced devices, materials and processes. Scientists, scholars and experts in the fields

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NDL National Nano Device Laboratories
國家奈米元件實驗室



時間: 中華民國96年5月9-15日

地點: 新竹市科學工業園區展業一路26號 奈米電子研究大樓 國際會議廳

奈米元件技術研討會 2007

主題

- 》後矽奈米電子元件技術
- 》奈米生物技術
- 》功能性奈米材料技術
- 》奈米檢測技術
- 》高頻技術及應用
- 》奈米光晶元件技術

Pulsed IV & Beyond

David Menzer,
President,
Auriga Measurement Systems

ABSTRACT

The value and efficacy of device modeling is becoming more accepted as improved models are developed and available within mainline simulators. However, analog, and microwave design has not reached the accuracy and common acceptance of first pass success because our models, and the data they are based on still requires improvement. In this paper we will look at the techniques in use today, their short comings and then examine some of the alternative device characterization techniques. We will look at Active Load Pull, Large Signal Network Analysis, Harmonic Load Pull, as well as some newer techniques that allow treatment of the baseband or other novel techniques.

Prior to forming Auriga Measurement Systems, David Menzer held the position of Director of Business Development for ACCO USA. There, he oversaw the development and execution of sales programs, corporate and product marketing, and identified and developed new business opportunities. In support of international sales, he cultivated and supported three sales representative organizations in Europe and Asia. During his tenure, two major products were introduced, and over ten major proposals were written resulting in three contracts, and five proposals in negotiation. A number of brochures and datasheets were also published under his direction.

Mr. Menzer received his Master of Science, Electrical Engineering and Bachelor of Science, Physics degrees from Rensselaer Polytechnic Institute in 1976 and 1975, respectively.